FORM PTO 1449 (mo	odified) J.S. DEPARTMENT OF COMMERCE	ATTY DOCKET NO. 03500.015727.1	APPLICATION NO.	NYA			
1	PATENT AND TRADEMARK OFFICE F REFERENCES CITED BY APPLICAN	ιτ(S)	APPLICANT	TAKEO TSUKA	мото		
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		U.S. F	PATENT DOCUMENTS				
'EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
AMH	6,624,589	9/03	Kitamura et al.	315	169.3		
AMH	6,628,053	9/03	Den et al.	313	310	·	
AMH	6,626,719	9/03	Ono et al.	445	24		
AMH	2002/0060516 A1	5/02	Kawate et al.	313	495		
AMH	2002/0031972 A1	3/02	Kitamura et al.	445	3		
RMH	2002/0057045 A1	5/02	Tsukamoto	313	309		
AMH	2002/0047513 A1	4/02	Nomura	313	495		
.AmH	2003/0006684 A1	1/03	Kawate et al.	313	311		
AmH	2003/0048055 A1	3/03	lshikura et al.	313	311		
AMH	2003/0057860 A1	3/03	Tsukamoto	315	169.3		
AMH	6,087,765	7/00	Coll et al.	313	309		
Amt	5,872,422	2/16/99	Xu et al.	313	311		
Ant	2002/0009637	1/02	Murakami et al.	429	213		
		FOREIG	N PATENT DOCUMENTS		y		
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
AMH	WO 01/93292	12/01	PCT				
ANH	10-149760	6/98	JAPAN			ABSTRACT	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE		ATTY DOCKET NO. 03500.015727.1		APPLICATION NO.			
	AND TRADEMARK OFFICE		APPLICANT				
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Date Submitted to PTO:	2.32.20		FILING DATE FILED HEREWITH			GROUP	2079 2817
			U.S. PATENT DOCUMENTS				
'EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AMH	4,728,851	3/88	Lambe		313	309	
AmH	4,904,895	2/90	Tsukamoto et al.		313	336	
AMH	5,986,389	11/99	Tsukamoto		313	309	·
Amt	6,147,449	11/00	iwasaki et al.	-	313	495	
AMH	6,171,162	1/01	lwasaki et al.		445	. 6	
AMH	6,184,610	2/01	Shibata et al.		313	309	·
AmH	6,231,413	5/01	Tsukamoto		445	24	
AMH	6,246,168	6/01	Kishi et al.		313	495	
AMH	6,288,494	6/01	Tsukamoto et al.		315	169.1	
AmH	5,982,091	11/99	Konishi		313	495	
			FOREIGN PATENT DOCUMEN	TS		·····	· · - · · · · · · · · · · · · · · · · ·
	DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AMH	0 614 209 A1	9/94	EPO				
DMH	8-115652	5/96	JAPAN		· · · · · · · · · · · · · · · · · · ·		ABSTRACT
DMH	7-6714	1/95	JAPAN		····		
BMH	0 290 026	11/88	EPO				ENGLISH
put	0 535 953 A2	4/93	EPO				ENGLISH
	01	HER DOCUME	NT(S) (Including Author, Title, Date	e, Pertir	nent Pages, Etc.)		
ANH ANH ANH			Properties of thin-Fil Physics, Vol. 47, No.				n Molybdenum
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FORM PTO 1449 (modified)			ATTY DOCKET NO. APPLICATION NO. NYA						
	U.S. DEPARTMENT OF COMPATENT AND TRADEMARK	OFFICE		APPLICANT TAKEO TSUKAMOTO					
LIST	OF REFERENCES CITED BY (Use several sheets if nece			FILING DATE GROUP 2679					
			B	FILING DATE FILED HEREWITH			21		
				U.S. PATENT DOCUMENTS	7				
'EXAMINER INITIAL	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
AMH	5,773,921	06/30/98		Keesman et al.	313	309			
Amt	5,973,444	10/26/99		Xu et al.	313	309			
AmH	5,935,639	8/10/99		Sullivan et al.	427	78			
AMH	4,956,578	9/11/90		Shimizu et al.	315	3			
Amlt	5,185,554	2/9/93		Nomura et al.	313	495			
AmH	6,448,709	9/02		Chuang et al.	313	497			
AmH	6,204,597	03/01	.	Xie et al.	313	310			
		,	FC	DREIGN PATENT DOCUMENTS					
	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
AMH	WO 89/07163	08/10/89		Japan			English		
MH	WO 90/07023	06/28/90		PCT			English		
AMH	JP 08-115652	05/07/96		Japan			Abst.& Transl.		
		OTHER DOCUME	ENT(S	6) (Including Author, Title, Date, Pertinent Pages, Etc.)					
BWH	R.T.K. Baker et Decomposition			f Carbonaceous Deposits from the 137 J. Catal. 101-105 (1975).	Platinun	n-Iron Cata	lyzed		
AMH	V .	Catalytic Grov	vth	of Carbon Filaments," 27 (3) Carbor	1 315-32	3 (1989).			
AMH	S. lijima, "Helic	al Microtubul	es c	of Graphitic Carbon," Nature, Vol. 34	5, 56-58	(1991).			
AMH	T. W. Ebbesen (1992).	et al., " Large-	-Sca	ale Synthesis of Carbon Nanotubes,	" Nature	, Vol. 358,	220-222		
ANH		W. A. DeHeer et al., "Aligned Carbon Nanotube Films: Production and Optical and Electronic Properties," Science Vol. 268, 845-847 (1995).							
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'EXAMINER	DOCUMENT			U.S. PATENT DOCUMENTS	T		FILING DATE		
INITIAL	NUMBER	DATE		NAME	CLASS	SUBCLASS	IF APPROPRIATE		
AmH	5,577,943	11/96		Vickers et al.	445	24			
AmH	2002/136896	09/26/00		Takikawa et al.	428	408			
AMH	5,192,240	03/09/93	_	Komatsu	445	24			
AmH	5,214,346	05/25/93		Komatsu	313	309			
AMH	5,382,867	01/17/95		Maruo et al.	313	309			
AMH	5,612,587	03/18//97		Itoh et al.	313	309			
Amt	6,313,572	11/06/01		Yamada	313	310			
			FO	REIGN PATENT DOCUMENTS					
	DOCUMENT NUMBER	DATE		COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
AMH	0 758 028 A2	02/12/97		EPO	D01F	9/127	English		
AMH	WO 98/05920	02/12/98		PCT	G01E	7/34	English		
AMH	0 394 698 A2	10/31/90		EPO	H01、	1/30	English		
AMH	2000/277003	06/10/00		Japan	H01、	9/02	No		
		OTHER DOCUM	MENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					
PMH	T. Guo et al., " Lett., Vol. 243,		wth	of Single- Walled Nanotubes by Las	er Vapo	orization," (Chem Phys.		
Derth Derth Derth Derth	A. G. Rinzler et 269, 1550-1553		ing N	Nanotubes: Field Emission from an A	Atomic	Wire," Scie	nce, Vol.		
ANH	W. A. DeHeer et al., "A Carbon Nanotube Field-Emission Electron Source," Science, Vol. 270, 1179-1180 (1995).								
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DWA	A. Thess et al., "Crystalline Ropes of Metallic Carbon Nanotubes," Science, Vol. 273 483-487 (1996).								
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FORM PTO 1449 (modified) ATTY DOCKET NO. APPLICATION NO. 03500.015727.1 NYA U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE APPLICANT **TAKEO TSUKAMOTO** LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) FILING DATE 2879 GROUP **FILED HEREWITH** U.S. PATENT DOCUMENTS **'EXAMINER** DOCUMENT FILING DATE INITIAL NUMBER DATE SUBCLASS NAME CLASS 6,135,839 10/24/00 lwase et al. 445 24 2002/0031972 3/02 Kitamura et al. 445 6/02 6,400,091 Deguchi et al. 169.1 315 AMH 6,420,726 7/02 Choi et al. 257 10 FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT DATE COUNTRY SUBCLASS CLASS YES/NO/ OR ABSTRACT NUMBER AMH 0 797 233 A2 09/24/97 **EPO** H01J 1/30 **English** 0 980 089 A1 02/16/00 **EPO** H01J 1/30 English 0 986 084 A2 03/15/00 **EPO H01J** 1/30 **English** 1 117 118 A1 07/08/01 **EPO** H01J 1/312 English 06/12/96 **EPO** 0716439 H01J 3/02 English 1 113 478 A1 7/01 **EPO** Abst. & corresponding **JAPAN** 2-112125 04/24/90 H01J 1/30 **U.S. Patent** 4,956,578 OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) DWH H. Dai et al., "Single-Wall Nanotubes Produced by Metal-Catalyzed Disproportionation of Carbon Monoxide," Chem. Phys. Lett., Vol. 260, 471-475 (1996). H. Dai et al., "Nanotubes as Nanoprobes in Scanning Probe Microscopy," Nature, Vol. 384, 147-150 (1996). A. C. Dillon et al., "Storage of Hydrogen in Single- Walled Carbon Nanotubes," Nature, Vol.386, 377-379 (1997). W.P. Dyke et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. 8, (1956) pp. 89-185 C.A. Spindt et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones", Journal of Applied Physics, Vol. 47, No. 12 (1976), pp. 5248-5263 DATE CONSIDERED 08/03/05

^{&#}x27;EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO. APPLICATION NO. NYA						
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port	3-20941	01/29/91		JAPAN	H01	J 31/12	Abst. & corresponding U.S. Patent 5,185,554		
ANH	5-211029	08/20/93		JAPAN	H01	J 1/30	No		
AMH	8-264109	10/11/96		JAPAN	H01	J 1/30	Abst.		
AMH	9-82214	3/28/97		JAPAN	H01	J 1/30	Abst. & European Equivalent 0 716 439		
AMH	1 113 478 A1	7/02		EPO					
AMH	1 122 344 A3	8/01		EPO		·			
AMH	A0 913 508	05/06/99		ЕРО	D01	F 9/127	English		
AMH	09-188600	07/22/97		Japan	C30	B 29/62	Abst.		
AMH	A1 443 865	08/28/91		EPO	H01	J 21/10	English		
		OTHER DOCUM	MENT(S	(Including Author, Title, Date, Pertinent Pages, Etc.)					
DWA	C.A. Mead, "Op (1961), pp. 646-		innel	-Emission Devices", Journal of App	lied Ph	nysics, Vol.	32, No. 4,		
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Burk		M.I. Elinson et al., "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide", Radio Engineering and Electronic Physics, (1965) pp. 1290-1296							
Derry	G. Dittmer, "Ele Solid Films, Vo			on and Electron Emission of Discont	tinuous	Thin Films	", Thin		

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	2001/0006232 A1	7/01		Choi et al.				
		FO	REIGN	PATENT DOCUMENTS				
	DOCUMENT NUMBER	DATE		COUNTRY	CLAS	S SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
Ant	04-212236	03/08/92		Japan	H01	J 1/30	No	
Amth	03-295131	12/26/91		Japan	H01	J 1/30	No	
AMH	A2 535 953	04/07/93		EPO	H01	J 1/30	English	
Amtt	05-159696	06/25/93		Japan	H01	J 1/30	No	
Amtt	05-198253	08/06/93		Japan	H01	J . 1/30	No	
AMH	05-274997	10/22/93		Japan	H01	J 1/30	Abst.	
Amth	11-232997	08/27/99		Japan	H01	J 1/30	No	
AMH	A1 936 650	08/18/99		EPO	H01	J 3/02	English	
Amt	10-289650	10/27/98		Japan	H01	J 1/30	No	
AMH	A1 871 195	10/14/98		EPO	H01	J 1/30	English	
	0	THER DOCUMENT(S) (Includ	ling Author, Title, Date, Pertinent Pages, Etc.)				
AMH	M. Hartwell et al., " Trans. Ed. Conf., (1			mission from Patterned Tin-Ind	dium O	xide Thin Fil	ms", IEEE	
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			U.S. PATENT DOCUMENTS			ı — — —	
'EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME .	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
PmH	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98	
Amt	5,847,495	12/98	Yamanobe et al.	313	310		
AMH	5,066,883	11/91	Yoshioka et al.	313	309		
AmH	6,455,021 B1	09/02	Saito	423	447.3	07/20/99	
Amy	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00	
Amt	6,283,812 B1	09/01	Jin et al.	445	24	01/25/99	
Amt	4,816,289	03/89	Komatsu et al	423	447.3		
Amt	5,443,859	08/95	Nagata	427	122		
Amth	5,618,875	04/97	Baker et al.	524	495		
AMH	5,690,997	11/97	Grow	427	249		
AmH	6,129,602	10/00	Yamanobe	445	24		
Amtt	6,228,904 B1	05/01	Yadav et al.	523	210		
Amt	6,333,016 B1	12/01	Resasco et al.	423	447.3	9/3/99	
AmH	6,413,487 B1	07/02	Resasco et al.	423	447.3	6/2/00	
Ant	6,445,006 B1	09/02	Brandes et al.	257	76	7/27/99	
Amt	5,981,305	11/99	Hattori	438	76		
Amtt	6,290,564 B1	9/01	Talin et al.	445	50	9/30/99	
Ant	5,458,784	10/95	Baker et al.	210	674	5/3/00	
Antt	6,331,690 B1	12/01	Yudasaka et al.	219	121.6		
Ant	5,965,267	10/99	Nolan et al.	428	408		

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Amt	6,390,612 B1	05/02	Kotaki et al.	347	85			
ANT	5,872,541	02/99	Yoshioka et al.	345	74			
Amtt	5,543,684	08/96	Kumar et al.	313	495			
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Amtt	5,500,200	3/96	Mandeville et al.	423	447.3			
Amtt	5,726,524	3/98	Debe	313	309			
Amtt	2002/0009637 A1	1/24/02	Murakami et al	429	213	2/5/01		
Amtt	2002/0047562 A1	04/25/02	Kitamura et al.	315	169.3	05/29/01		
Amt	5,770,918	6/98	Kawate et al.	313	495			
+Amtt	5,185,554	2/93	Nomura et al.	313	495			
Amtt	2002/0146958 A1	10/02	Ono et al.	445	24			
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FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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ATTY DOCKET NO.

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Amit	11-194134	07/99	Japan	G01N	37/00	Abst., European Equivatent 0 913 508 A3			
AMH	11-139815	05/99	Japan	C01B	31/02	Abst.			
AMH	0 535 953 B1	01/96	EPO	H01J	1/30	English			
AMH	1 122 344 A2	08/01	EPO	D01F	9/127	English			
AMH	0 758 028 B1	09/11/02	EPO	D01F	9/127	English			
AMH	11-232997	08/27/99	Japan	H01J	1/30	European Counterpart 0 936 650			
AMH	1 022 763 A1	7/00	EPO	H01J	9/02	English			
AMH	2000-223005	8/00	Japan	H01J	1/304	Abst. & Counterpart U.S. Patent 6,283,812			
AMH	0 836 217 A1	04/98	EPO	H01J	29/94	English			
AMH	WO 99/58748	11/99	PCT	D01F	9/127	English			
AHH	CN 1181607A	5/98	China			English Counterparts 0 836 217 & 99/58748			
AMH	1 102 299 A1	5/01	EPO	H01J	1/30	English			
AMH	0 913 508 A3	5/99	EPO	D01F	9/127	English			
AMH	1 096 533 A1	5/01	EPO	H01J	9/02	English			
AMH	WO 01/26130	4/01	PCT	H01J	9/02	English			
AMH	GB 2 308 495 A	6/97	UK	H01J	1/20	English			
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AMH	1-309242	12/89	Japan	H01J	37/06	Abst.		
AMH	11-162334	6/99	JAPAN	H01J	9/02	Abst.		
AMH	2000-57934	2/00	JAPAN	H01J	1/304	Abst.		
AMH	2000-86216	3/00	JAPAN	C01B	31/02	Abst.		
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified)			ATTY DOCKET NO. 03500.015727.1	APPLICATION NO. NYA					
		S. DEPARTMENT OF COMMERCE TENT AND TRADEMARK OFFICE							
LIST	OF F	REFERENCES CITED BY APPLICANT(S)	TAKEO TSUKAMOTO						
	(Use several sheets if necessary)	FILING DATE GROUP 2879						
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